

October 1988 Revised August 1999

# 74F2243

# Quad Bus Transceiver with 25 $\Omega$ Series Resistors in the Outputs

#### **General Description**

The 74F2243 is a quad bus transmitter/receiver which can be used for 4-line asynchronous 2-way data communications between data busses. It is designed to drive the capacitive inputs of MOS memory drivers, address drivers, clock drivers, and bus-oriented transmitters/receivers.

The  $25\Omega$  series resistors in the outputs reduce ringing and eliminate the need for external resistors.

#### **Features**

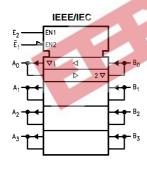
- $\blacksquare$  25 $\Omega$  series resistors in outputs eliminate the need for external resistors
- 2-Way asynchronous data bus communication
- 3-STATE outputs
- 12 mA source current
- Designed to drive the capacitive inputs of MOS devices

# **Ordering Code:**

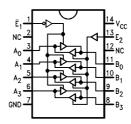
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Order Number	Package Number	Package Description
74F2243SC	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code

# **Logic Symbol**



# **Connection Diagram**



#### **Truth Table**

Inputs		Inputs/Outputs			
E <sub>1</sub>	E <sub>2</sub>	A <sub>n</sub>	B <sub>n</sub>		
L	L	Input	B = A		
L	Н	N/A	N/A		
Н	L	Z	Z		
Н	Н	A = B	Input		

H = HIGH Voltage Level L = LOW Voltage Level Z = High Impedance N/A = Not Allowed

### **Unit Loading/Fan Out**

Pin Names	Description	U.L.	Input I <sub>IH</sub> /I <sub>IL</sub>	
Pin Names	Description	HIGH/LOW	Output I <sub>OH</sub> /I <sub>OL</sub>	
E <sub>1</sub>	Enable Input (Active LOW)	1.0/1.67	20 μA/–1 mA	
$E_2$	Enable Input (Active HIGH)	1.0/1.67	20 μA/–1 mA	
$A_n, B_n$	Inputs	3.5/2.67	70 μA/–1.6 mA	
	Outputs	750/20	–15 mA/12 mA	

## Absolute Maximum Ratings(Note 1)

# Recommended Operating Conditions

Storage Temperature  $-65^{\circ}\text{C}$  to +150  $^{\circ}\text{C}$ 

 $\begin{array}{ll} \mbox{Ambient Temperature under Bias} & -55^{\circ}\mbox{C to } +125^{\circ}\mbox{C} \\ \mbox{Junction Temperature under Bias} & -55^{\circ}\mbox{C to } +150\mbox{C} \\ \end{array}$ 

 $\begin{array}{lll} \text{V}_{\text{CC}} \text{ Pin Potential to Ground Pin} & -0.5 \text{V to } +7.0 \text{V} \\ \text{Input Voltage (Note 2)} & -0.5 \text{V to } +7.0 \text{V} \\ \text{Input Current (Note 2)} & -30 \text{ mA to } +5.0 \text{ mA} \\ \end{array}$ 

Voltage Applied to Output in HIGH State (with  $V_{CC} = 0V$ )

Standard Output -0.5V to  $V_{CC}$ 3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated  $I_{OL}$  (mA) ESD Last Passing Voltage (Min) 4000V

Free Air Ambient Temperature  $0^{\circ}\text{C} \text{ to } +70^{\circ}\text{C}$  Supply Voltage +4.5V to +5.5V

**Note 1:** Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

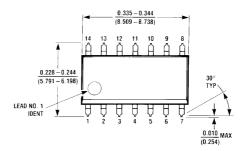
#### **DC Electrical Characteristics**

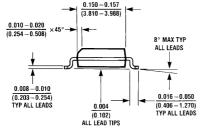
DC LI	Do Electrical Gilaracteristics							
Symbol	Parameter	Min	Тур	Max	Units	V <sub>CC</sub>	Conditions	
V <sub>IH</sub>	Input HIGH Voltage	2.0		-35-	V	-40	Recognized as a HIGH Signal	
V <sub>IL</sub>	Input LOW Voltage			0.8	V	CV.	Recognized as a LOW Signal	
V <sub>CD</sub>	Input Clamp Diode Voltage		36	<b>-1</b> .2	V	Min	I <sub>IN</sub> = -18 mA	
V <sub>OH</sub>	Output HIGH 10% V <sub>CC</sub>	2.4	13	-	100		$I_{OH} = -3 \text{ mA } (A_n, B_n)$	
	Voltage 10% V <sub>CC</sub>	2.0			V	Min	$I_{OH} = -15 \text{ mA } (A_n, B_n)$	
	5% V <sub>CC</sub>	2.7					$I_{OH} = -3 \text{ mA } (A_n, B_n)$	
V <sub>OL</sub>	Output LOW	$u_{I}$		0.50	V	Min	$I_{OL} = 1 \text{ mA } (A_n, B_n)$	
	Voltage			0.75	·	141111	$I_{OL} = 12 \text{ mA } (A_n, B_n)$	
I <sub>IH</sub>	Input HIGH Current			20	μΑ	Max	$V_{IN} = 2.7V (\overline{E}_1, \overline{E}_2)$	
I <sub>BVI</sub>	Input HIGH Current			100	μА	Max	$V_{IN} = 7.0V (\overline{E}_1, E_2)$	
	Breakdown Test			100	μΑ	IVIAX	$v_{IN} = 7.0v (E_1, E_2)$	
I <sub>BVIT</sub>	Input HIGH Current			1.0	mA	Max	V <sub>IN</sub> = 5.5V (A <sub>n</sub> , B <sub>n</sub> )	
	Breakdown Test (I/O)			1.0	IIIA	IVIGA	$V_{\rm IN} = 3.3V (\Lambda_{\rm IN}, D_{\rm IN})$	
I <sub>IL</sub>	Input LOW Current			-1.0	mA	Max	$V_{IN} = 0.5V (\overline{E}_1, E_2)$	
I <sub>IH</sub> + I <sub>OZH</sub>	Output Leakage Current			70	μΑ	Max	$V_{OUT} = 2.7V (A_n, B_n)$	
I <sub>IL</sub> + I <sub>OZL</sub>	Output Leakage Current			-1.6	mA	Max	$V_{OUT} = 0.5V (A_n, B_n)$	
los	Output Short-Circuit Current	-100		-225	mA	Max	$V_{OUT} = 0V (A_n, B_n)$	
I <sub>CEX</sub>	Output HIGH Leakage Current			250	μΑ	Max	$V_{OUT} = V_{CC}$	
I <sub>CCH</sub>	Power Supply Current		64	80	mA	Max	V <sub>O</sub> = HIGH	
I <sub>CCL</sub>	Power Supply Current		64	90	mA	Max	$V_O = LOW$	
I <sub>CCZ</sub>	Power Supply Current		71	90	mA	Max	V <sub>O</sub> = HIGH Z	

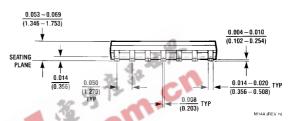
#### **AC Electrical Characteristics**

Symbol	Parameter	$T_{A} = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$			$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$ $C_L = 50$ pF		Units	
		Min	Тур	Max	Min	Max		
t <sub>PLH</sub>	Propagation Delay	1.5		7.0	1.5	7.0	ns	
t <sub>PHL</sub>	$A_n$ to $B_n$ , $B_n$ to $A_n$	2.5		8.0	2.0	8.0	115	
t <sub>PZH</sub>	Output Enable Time	1.5		9.0	1.0	9.5		
$t_{PZL}$	$\overline{E}_1$ to $B_n$ , $E_2$ to $A_n$	2.5		11.5	2.5	12.0	ns	
t <sub>PHZ</sub>	Output Disable Time	1.5		9.0	1.0	9.5	110	
$t_{PLZ}$	$\overline{E}_{1}$ to $B_{n}$ , $E_{2}$ to $A_{n}$	1.5		8.5	1.5	9.5		

#### Physical Dimensions inches (millimeters) unless otherwise noted







14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow Package Number M14A

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